



Product Change Notice

Micron PCN: 30542
 Date: 10/31/2011

Type of Change:	Die Shrink, End of Life	
Title of Change:	137b T69M based MCP's EOL/Die Shrink	
Description of Change:	<p>50nm 137b T69M based MCP's will be replaced with either 42nm T79M DRAM shrink or 42nm DRAM and 25nm NAND shrink.</p> <p>The DRAM only shrink will support chipsets that can accommodate 4bit ECC. The DRAM and NAND shrink will support chipsets that can accommodate 8bit ECC.</p>	
Reason for Change:	Better align industry standards, Optimization of Manufacturing Efficiency	
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Product Affected: 137b T69M based MCP's

Affected Micron Part Number	Replacement - 4bit ECC	Replacement - 8bit ECC
MT29C4G48MAYAPAKD-5 IT	MT29C4G48MAYBAAKS-5 WT	MT29C4G48MAAGBAAKS-5 WT
MT29C4G48MAYAPAKD-6 IT	MT29C4G48MAYBAAKS-5 WT	MT29C4G48MAAGBAAKS-5 WT
MT29C4G48MAZAPAKD-5 E IT	none	none
MT29C4G48MAZAPAKD-5 IT	MT29C4G48MAZBAAKS-5 WT	MT29C4G48MAAHBAAKS-5 WT
MT29C4G48MAZAPAKD-6 IT	MT29C4G48MAZBAAKS-5 WT	MT29C4G48MAAHBAAKS-5 WT
MT29C4G96MAYAPCJA-5 IT	MT29C4G96MAYBACKD-5 WT	MT29C4G96MAAGBACKD-5 WT
MT29C4G96MAZAPCJA-5 E IT	none	none
MT29C4G96MAZAPCJA-5 IT	MT29C4G96MAZBACKD-5 WT	MT29C4G96MAAHBACKD-5 WT
MT29C4G96MAZAPCJA-6 IT	MT29C4G96MAZBACKD-5 WT	MT29C4G96MAAHBACKD-5 WT
MT29C8G96MAYAPDJA-5 IT	MT29C8G96MAYBADKD-5 WT	MT29C8G96MAAEBACKD-5 WT
MT29C8G96MAYAPDJA-6 IT	MT29C8G96MAYBADKD-5 WT	MT29C8G96MAAEBACKD-5 WT
MT29C8G96MAZAPDJA-5 IT	MT29C8G96MAZBADKD-5 WT	MT29C8G96MAAFBACKD-5 WT
MT29C8G96MAZAPDJA-6 IT	MT29C8G96MAZBADKD-5 WT	MT29C8G96MAAFBACKD-5 WT

Micron Sites Affected: All Sites

42nm T79M Based Product

Sample Availability Date: Dec 2011
Qual Data Availability Date: Jan 2012
Product Ship Date: Feb 2012

50nm T69M Based Product

Last Time Buy: 1-Jun-2012
Last Time Ship: 1-Dec-2012

Note: Per JEDEC Standard JESD46-C Section 3.2.3; lack of acknowledgment of this PCN within 30 days constitutes acceptance of change